

Publikationen

- (2018): Protective nanometer films for reliable Cu-Cu connections. Invited Talk. In: IEEE International Reliability Physics Symposium (IRPS), San Francisco, CA, USA.
- (2017): Protective nanometer films for reliable Cu-Cu connections. Best Paper Award. In: Proceedings of the 28th European Symposium on Reliability of Electron Devices, Failure Physics and Analysis (ESREF) [25-28 September, 2017; Bordeaux, Frankreich].
- (2017): Numerical Study of Hydrodynamic Forces for AFM Operations in Liquid Scanning (Article ID 6286595, 12 pages). In: Scanning, no. Article ID 6286595, pp. 1-12. DOI: 10.1155/2017/6286595.
- (2017): Protective nanometer films for reliable Cu-Cu connections. In: Microelectronics Reliability, vol. 76-77, no. September, pp. 383-389. DOI: 10.1016/j.microrel.2017.07.001.
- (2016): Nanoscale electrical conductivity of laser-sintered Ge nanoparticle layers. In: The 8th International Conference On Technological Advances Of Thin Films and Surface Coatings (ThinFilms 2016), Singapur, Singapur.
- (2016): Nanoscale characterization of laser-sintered Ge nanoparticle layers. In: 2nd International Conference on Functional Integrated nano Systems (nanoFIS), Graz, Österreich.
- (2015): Ordered arrangement of irradiation-induced defects of polycrystalline tungsten irradiated with low-energy hydrogen ions. In: Journal of Nuclear Materials, vol. 464, pp. 216-220.
- (2015): Observation of interstitial loops in He⁺ irradiated W by conductive atomic force microscopy. In: Acta Materialia, vol. 92, pp. 178-188.
- (2015): Nanoscale characterization of CH₃-terminated Self-Assembled Monolayer on copper by advanced scanning probe microscopy techniques. In: Applied Surface Science, vol. 356, pp. 921-926. DOI: 10.1016/j.apsusc.2015.08.182.
- (2015): Nanoscale characterization of copper oxide films by Kelvin Probe Force Microscopy. In: Thin Solid Films, vol. 584, no. June 2015, pp. 310-315. DOI: 10.1016/j.tsf.2015.01.071.
- (2014): Characterization of Self-Assembled Monolayers on Copper by Scanning Probe Microscopy. In: 16th International Conference on Thin Films (ICTF16), Dubrovnik, Kroatien.
- (2014): Nanoscale copper oxide characterization with Kelvin Probe Force Microscopy. Posterpräsentation. In: The 7th International Conference on Technological Advances of Thin Films & Surface Coatings (THINFILMS2014), Chongqing, China.
- (2014): Selected Atomic Force Microscopy Methods for the Electrical Characterization of Thin Films and Devices. Invited Talk. In: 4th International Advances in Applied Physics and Materials Science Congress & Exhibition (APMAS), Fethiye, Türkei.
- (2012): Analysis of copper oxide films by combined scanning microscopy. In: 6th International Conference on Technological Advances of Thin Films & Surface Coatings (THINFILMS2012), Singapur, Singapur.